



Direct protein crystallization on ultrathin membranes for diffraction measurements at X-ray free-electron lasers. Corrigendum

Nadia Opara,^{a,b,c,*} Isabelle Martiel,^a Stefan A. Arnold,^{b,c} Thomas Braun,^{b,c} Henning Stahlberg,^{b,c} Mikako Makita,^a Christian David^a and Celestino Padeste^{a,c}

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‡ As of March 2019 the PSI domain corresponding author's address became obsolete; prospective questions on the content of the article can be directed to nadia.opara@gmail.com.

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^aPaul Scherrer Institute (PSI), 5232 Villigen, Switzerland, ^bCenter for Cellular Imaging and NanoAnalytics (C-CINA), Biozentrum, University of Basel, Basel 4058, Switzerland, and ^cSwiss Nanoscience Institute, University of Basel, Basel 4056, Switzerland. *Correspondence e-mail: nadia.opara@gmail.com

Errors in the article by Opara, Martiel, Arnold, Braun, Stahlberg, Makita, David & Padeste [*J. Appl. Cryst.* (2017), **50**, 909–918] are corrected.

In the article by Opara *et al.* (2017), the chemical formula of the silicon nitride was given erroneously. No detailed structural analysis was performed, and no experimental evidence is provided to justify the claim that all of the silicon nitride membranes used in the presented experiments had stoichiometric composition (Yang & Pham, 2018). Therefore, the formula describing the specific case Si₃N₄ should be replaced with the generic formula Si_xN_y.

In addition, there was a typographical error in the unit of ultrapure water resistivity, which should be MΩ cm.

References

- Opara, N., Martiel, I., Arnold, S. A., Braun, T., Stahlberg, H., Makita, M., David, C. & Padeste, C. (2017). *J. Appl. Cryst.* **50**, 909–918.
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